

Notice of References Cited	Application/Control No. 10/040,433	Applicant(s)/Patent Under Reexamination YOSHIMURA ET AL.	
	Examiner Dah-Wei D. Yuan	Art Unit 1745	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,190,803	02-2001	Tomiyama et al.	429/245
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	J	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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